

Title (en)

SENSOR OPENING TEST SYSTEM, SENSOR OPENING TEST MANAGEMENT TERMINAL, SENSOR, SENSOR OPENING TEST METHOD AND PROGRAM

Title (de)

SENSORÖFFNUNGSTESTSYSTEM, ENDGERÄT ZUR VERWALTUNG EINES SENSORÖFFNUNGSTESTS, VERFAHREN UND PROGRAMM FÜR SENSORÖFFNUNGSTEST

Title (fr)

SYSTÈME D'ESSAI D'OUVERTURE DE CAPTEUR, TERMINAL DE GESTION D'ESSAI D'OUVERTURE DE CAPTEUR, CAPTEUR, PROCÉDÉ D'ESSAI D'OUVERTURE DE CAPTEUR ET PROGRAMME

Publication

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Application

EP 17869549 A 20170921

Priority

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- JP 2017034017 W 20170921

Abstract (en)

[origin: EP3541084A1] The present invention is provided with a sensor-side metadata acquiring unit (10) that acquires sensor-side test metadata, an application-side metadata acquiring unit (11) that acquires application-side test metadata, a matching unit (12) that determines matching of acquired sensor-side test metadata and acquired application-side test metadata, and a dataflow control command instructing unit (13) that transmits a dataflow control command instructing test data flow to an opening test application from a sensor (1a-1c) or network adaptor (2) specified by matched sensor-side test metadata and the application-side test metadata.

IPC 8 full level

H04Q 9/00 (2006.01); **G06F 11/22** (2006.01)

CPC (source: EP US)

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Citation (search report)

- [X] US 2008208367 A1 20080828 - KOEHLER MICHAEL [DE], et al
- [X] US 2016210862 A1 20160721 - HISANO ATSUSHI [JP]
- [X] US 2012089708 A1 20120412 - KIM MAL HEE [KR], et al
- See references of WO 2018088039A1

Designated contracting state (EPC)

AL AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO RS SE SI SK SM TR

Designated extension state (EPC)

BA ME

DOCDB simple family (publication)

EP 3541084 A1 20190918; **EP 3541084 A4 20200101**; **EP 3541084 B1 20220330**; JP 2018082248 A 20180524; JP 6406336 B2 20181017; US 11106558 B2 20210831; US 2019258553 A1 20190822; WO 2018088039 A1 20180517

DOCDB simple family (application)

EP 17869549 A 20170921; JP 2016221798 A 20161114; JP 2017034017 W 20170921; US 201716346550 A 20170921